Defect Origin

Where Found	RQ	High Level Design	Low Level Design	Code	Unit Test	Com-ponent Test	System Test	Field	
RQ	--								0
I0	49	681							730
I1	6	42	681						729
Code	12	28	114	941					1095
UT	21	43	43	223	2				332
CT	20	41	61	261	--	4			387
ST	6	8	24	72	--	--	1		111
Field	8	16	16	40	--	--	--	1	81
Total	122	859	939	1537	2	4	1	1	3465

RQ =	(0/ (122 + 0)) * 100	=	0 %
I0 =	(730 / (859 + (122 - 0)) * 100	=	74.41 %
I1 =	(729 /(939 + ((859 + 122) - (730 + 0))) * 100	=	61.26 %
Code =	(1095 /(1537 + (939 + 859 + 122) - (729 + 730 + 0)) * 100	=	54.8 %
UT =	(332 /(2 + (1537 + 939 + 859 + 122) - (1095 + 729 + 730 + 0)) * 100	=	36.69 %
CT =	(387/(4 + (2+1537+939+859+122) - (332+1095+729+730+0)) * 100	=	67.07 %
ST =	(111 /(1 + (4+2+1537 + 939 + 859 + 122) - (387 + 332 + 1095 + 729 + 730 + 0)) * 100	=	58.12 %
Field =	(81 /(1 + (1+4+2+1537 + 939 + 859 + 122) - (111 + 387 + 332 + 1095 + 729 + 730 + 0)) * 100	=	100 %
Total =	(1+1+4+2+1537 + 939 + 859 + 122) / (111 + 387 + 332 + 1095 + 729 + 730 + 0)) * 100	=	100 %

Overall Efficenecy of them RQ+I0+I2+code	(1537 + 939 + 859 + 122) / (1095 + 729 + 730 + 0)) * 100	73.88%